

Notice of References Cited	Application/Control No. 10/623,476	Applicant(s)/Patent Under Reexamination BLAISDELL ET AL.	
	Examiner Ajay Vasudeva	Art Unit 3617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,079,669	06-2000	Hanay et al.	244/118.5
	B	US-6,007,025	12-1999	Coughren et al.	244/118.6
	C	US-1,409,330	03-1922	APER ANNA B	312/228
	D	US-345,890	07-1886	Farson	4/420.3
	E	US-316,324	04-1885	Barnwell	4/664
	F	US-200,480	02-1878	Rivera	312/226
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200101832 A1	01-2001	World Intellect	HASTED, R F	A47K 03/06
X	O	JP 2000027270 A	01-2000	Japan	TSUCHIDA, YUKINORI	E03D 11/00
	P	FR 2754504 A1	04-1998	France	HYMER, ERWIN	B60R 15/04
	Q	JP 64029240 A	01-1989	Japan	TONOO, YOSHIHIRO	A47K 04/00
	R	WO 7900790 A	10-1979	World Intellect	BURKE et al.	A47K 01/06
	S	DE 2423561 A	11-1975	Germany		B60R 15/04
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.